Interaction Corrections to Two-D im ensional Hole Transport in Large r_s Lim it

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The m etallic conductivity of dilute two-dimensional holes in a GaAsHIGFET (Heterojunction Insulated-GateField-E ect Transistor) with extremely high mobility and large $r_{\rm s}$ is found to have a linear dependence on temperature, consistent with the theory of interaction corrections in the ballistic regime. Phonon scattering contributions are negligible in the temperature range of our interest, allowing comparison between our measured data and theory without any phonon subtraction. The magnitude of the Fermi liquid interaction parameter F_0 determined from the experiment, however, decreases with increasing $r_{\rm s}$ for $r_{\rm s}$ > 22, a behavior unexpected from existing theoretical calculations valid for small $r_{\rm s}$.

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In two-dimensional (2D) charge carrier systems, it is wellknown that any amount of disorder in the absence of interactions between the carriers will localize the carriers, leading to an insulator with zero conductivity () as the tem perature (T) is decreased to zero 1 . Recent experim ents on high m obility dilute 2D system s, on the other hand, have shown a \m etallic" behavior at low T, characterized by an increasing with decreasing T, and an apparent m etal-insulator transition (M II) as the carrier density is low ered². There are three important energy scales in these systems. The rst two are the Fermienergy and the interaction energy. Their ratio, which is rs, is around 10 or higher for the systems where the M II is observed, implying that interaction must be playing a role. The other energy scale is related to the disorder in the system given by h= , where is the elastic scattering time. It has been found from more recent experiments that disorder is also playing a signi cant role. In particular, the critical density (nc for electrons and pc for holes), above which a system shows the metallic behavior, is found to decrease when disorder in the 2D system is decreased³.

An important question is whether this apparent metallic state is truly a new ground state of the 2D charge carriers or simply a novel nite temperature behavior of the 2D gas, since all experim ents are done at nite T. W hat is measured in such experiment is the temperature coe cient, d =dT. The m etallic behavior evinced by the observation of negative d =dT at nite T does not necessarily m ean, however, a true m etal with nonzero conductivity at T = 0. Recently, Zala et al. calculated the Ferm i liquid interaction corrections to the conductivity in the asymptotic low temperature regime ($T = T_F$ where T_F is the Ferm i tem perature), and pointed out that the m etallic behavior seen in the high m obility sam ples could be understood by taking into account of interaction corrections in the \high tem perature" ballistic regime (k_B T h=). They found that the conductivity

of interacting 2D carriers changes linearly with T in the ballistic regime, $T_{\rm F}$ T $h\!=\!k_{\rm B}$, with the sign as well as the magnitude of d =dT depending on the strength of the interaction, while in the low temperature diusive regime ($k_{\rm B}$ T $h\!=\!$) the conventional logarithmically changing conductivity 5 is recovered. A linear dependence of on T has also been predicted in earlier theories 6,7 based on temperature dependent screening, and this screening contribution is included in the theory by Zala et al.

Experim entally, however, it is not straightforward to identify the interaction corrections unequivocally in the ballistic regim e for two main reasons. First, scattering by phonons can give signi cant contributions at high tem peratures. In order to have the ballistic regime at sufciently low T to minimize the phonon contributions, the 2D charge carrier system must have a very high mobility so that $h=k_B$ becomes very low. Second, the tem perature constraint, TF Τ h=k_B , satisfying the dual conditions of being in the ballistic regime (i.e. h=kB, which is a high-tem perature constraint) and of also being in the asymptotic low temperature regime of T_F (so that the therm alexpansion in $T=T_F$, essential for obtaining the linear-T term in the conductivity, applies) is not easily satis ed experim entally, and indeed most experimentally measured (T) data in 2D systems do not manifest any clear cut linear-T behavior at low tem peratures. An additional issue we are addressing in this work is whether the theory of interaction corrections to the conductivity can describe 2D transport in the large rs lim it as well. This is particularly germ ane in view of the fact that the interaction theory is a system atic manybody diagram matic expansion in the interaction param eter r_s (albeit an in nite order form al expansion), and the question of the radius of convergence of such an r_s expansion becomes quite important for large rs values obtained in our sam ples.

In this paper, we report our experiments on the low

tem perature conductivity and the in-plane magnetoresistance (MR) of two-dimensional (2D) holes with extremely high mobility and very low density (rs 17 to 80) to study the interaction corrections. From the temperature dependence of conductivity, we clearly observed a temperature region where the the conductivity shows a linear dependence on T even in this large $r_{\rm S}$ limit for a range of densities in the metallic side of the transition. However, the Fermi liquid interaction parameter F_0 , determined from a comparison of the data with the theory by Zala et al. 4 , shows a surprising non-monotonic dependence on the carrier density with its value lying between 0.5 and 0.7. Expresses in magnitude with decreas-

 $0.5~{\rm and}~0.7.~F_0$ increases in m agnitude with decreasing density for p $^>$ 2 $~10^{10}~{\rm cm}^{-2}~(r_{\rm s}$ $^<$ 22) and then decreases with decreasing density for p $^<$ 2 $~10^{10}~{\rm cm}^{-2}~(r_{\rm s}$ $^>$ 22), a behavior unexpected from a simple extrapolation of the predicted dependence of F_0 on small $r_{\rm s}$. A separate m easurem ent of elective g-factor (g) from the in-plane M R provides a further con m ation of the unexpected behavior of F_0 . g decreases with decreasing density, consistent with the behavior expected from F_0 for p $^<$ 2 $~10^{10}~{\rm cm}^{-2}$ through g = $g_b = (1 + F_0)$.

The sample used in this study is a heterojunction insulated-gate eld-e ect transistor (HIGFET) made on a (100) surface of G aA s^8 . A m etallic gate, separated by an insulator (A LG aAs) from the sem iconducting GaAs, is used to induce the 2D holes at the interface between the GaAs and AlGaAs. Ohmic contacts to the 2D holes are made by using a self-aligned contact technique which allows the diusion of the contact material under the gate region. We would like to emphasize that there is no intentional doping in the sam ple and the 2D holes are induced by the applied gate voltage. This reduces the scattering by ionized impurities so signicantly that a very high mobility can be achieved. The mobility () of the sample reaches 1:8 10^6 cm²/V s at a density (p) of 3:2 cm², which is the highest achieved for 2D holes in this low density regime. This high mobility makes h=kB for 10^{10} cm 2 range from 16 mK to 80p = 32 to 0.7m K, low enough that the tem perature region where the m etallic behavior is observed indeed corresponds to the ballistic regime while phonon contributions are negligible. The extrem ely high mobility also allows us to measure the tem perature dependence of conductivity down to very low densities reaching p = 1:5 10^9 cm 2 , with r_s near 80 (assuming a hole mass of 0:38m $_e$).

In Fig. 1, we show the temperature dependence of the resistivity () at various densities. For p $1.7\,\,$ 10^0 cm 2 , decreases monotonically with decreasing T, showing a metallic behavior. For p between 1.2 and 0.4 $\,\,$ 10^{10} cm 2 shows a nonmonotonic dependence on T. It initially increases with decreasing T at high T, which was interpreted as the classical to quantum crossover 7 , and then decreases with decreasing T at low T showing a metallic behavior as the system goes into the degenerate regime. This crossover shifts to lower temperature with decreasing density and the range where the metallic behavior is seen becomes very narrow, especially

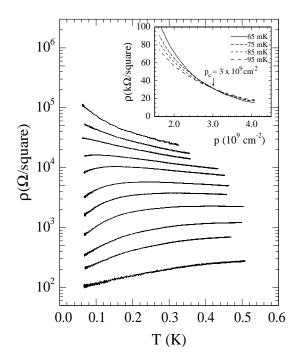


FIG.1: vsT for p = 32,22,17,12,0.9,0.7,0.5,0.4,0.3,0.23, and 0.15 10^{10} cm 2 from the bottom . The inset shows measured as a function of p at dierent T's. The critical density p_c is marked by an arrow corresponding to a point where is temperature independent.

forp = 0.5 and 0.4 10^{10} cm 2 . Forp $3 \quad 10^{\circ} \text{ cm}^{-2}$ increases m onotonically with decreasing T, exhibiting an insulating behavior. To identify the critical density, we m easured as a function of p at di erent tem peratures and the data is shown in the inset. The critical density determined from the crossing point, which shows a tem perature independent resistivity, is $p_c = 3$ 10^9 cm^{-2} . This low critical density, the lowest ever observed in 2D systems which exhibit the MII, is consistent with the previous observation by Yoon et al.3 that the critical density becomes lower with decreasing disorder in the system. If we use the hole e ective mass m = 0.38m e, this critical density corresponds to $r_s = 57$, which is much larger than the $r_s = 37$ predicted for the W igner crystallization in 2D 9.

In Fig. 2 (a), we replot the data for $p=3.2 ext{ } 10^{10} ext{ cm}^2$ to $0.7 ext{ } 10^{10} ext{ cm}^2$ as $ext{ vs T}$. The data are scaled by $ext{ } 0.7$ the value of extrapolated to $ext{ T}=0$, and o set by 0.1 for clarity. The m etallic behavior is identified by increasing with decreasing T at low T for all these densities. Clearly, there is a region where shows a linear dependence on T as shown by the best to in the gure with solid lines. We note that $ext{ rs }$ for these densities ranges from 17 to 37 and shows a linear dependence on T for such large $ext{ rs }$. To compare our results with the theory by Zala et al. 4, we need to consider several points. First, as discussed below phonon contributions are negligible in the temperature range where the linear dependence is

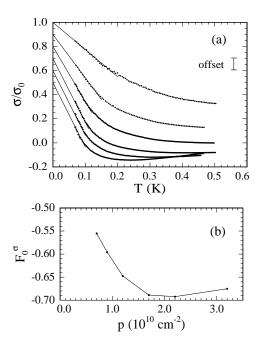


FIG. 2: (a) vsT forp= 32,22,1.7,12,0.9, and $0.7 \cdot 10^{10}$ cm² from the top. The data are scaled by the value extrapolated to T = 0, and o set by 0.1 for clarity. The solid line for each curve is a linear t in the low temperature region of the data. (b) F_0 vsp.

observed, which is below 200 m K for $p = 3.2 ext{ } 10^{10} ext{ am}^{-2}$ and becom es low er for low er densities. Second, this linear region is in the ballistic regim e $(k_B T > h =) since h = k_B$ calculated from $_0$ ranges from $16 \, \text{m K}$ for p = 3.2cm 2 to 80 m K for p = 0:7 10^{10} cm 2 . Finally, this region is also much lower than the Ferm item perature (T_F) of the system, which is 500 mK for the lowest density 10^{10} cm 2 . Zala et al. have pointed out that p = 0:7the regim $ewhere F_0$ can be treated as a m om entum inde- $(1+F_0)^2T_F$. A self-consistency pendent constant is T check after we have determined F_0 approximately (but som ew hat weakly) satis es this condition. All these allow a direct comparison of our data with their theory. From their theory, the slope of this linear dependence is directly related to the Ferm i liquid interaction param eter F_0 by the relation

S lope =
$$\frac{m k_B}{h^2 p}$$
 1 + $\frac{3F_0}{(1 + F_0)}$: (1)

U sing m = 0:38m $_{\rm e}$ (which was obtained from cyclotron resonance of high density (p = 5 $\,$ 10 $^{\rm l}$ cm $^{\rm 2}$) 2D holes on (100) surface of G aA s $^{\rm l0}$), we have obtained from our data F $_{\rm 0}$ as a function of p. The result is shown in Fig. 2 (b). The value of F $_{\rm 0}$ lies between $\,$ 0:5 and 0:7 in the density range we measured from 32 $\,$ 10 $^{\rm l0}$ cm $^{\rm 2}$ to 0:7 $\,$ 10 $^{\rm l0}$ cm $^{\rm 2}$. For p $^{\rm 2}$ 2 $\,$ 10 $^{\rm l0}$ cm $^{\rm 2}$ (r $_{\rm s}$ $^{\rm 4}$ 22), the magnitude increases with decreasing density. Proskuryakov et al. $^{\rm l1}$ have also found that F $_{\rm 0}$ for 2D holes in (311)A G aA s/A IG aA s heterostructure increases

in magnitude with decreasing p for p = 2 to 8 cm² with values between 0:3 and 0:45. The change of F $_{0}\,$ perdensity is sim ilar in both experim ents, while the m agnitude of F_0 in our m easurem ent is much larger. W e note that F_0 found from experim ents on 2D electrons in Si-M O SFE $\check{\mathbf{T}}^{12}$ also has much sm aller magnitude, ranging 0:14 to 0:5 for electron densities 1 to 40 cm², while the value found from p-SiGe by Coleridge et al. is som ew hat com parable to ours, between 0:65. W hat is surprising in our experiment, which explores the much lower density (larger r_s) regime, is that the magnitude of F_0 does not increase monotonically with decreasing density. When the density is decreased below 2 $\,$ 10 0 cm 2 (rs $^{>}$ 22) the magnitude of F $_{\scriptsize 0}$ decreases again . This is opposite to the predicted dependence of F $_{0}\,$ on $\,r_{s}\,$ valid for small $\,r_{s}\,$. To our best know ledge, the dependence of F_0 on r_s when r_s is large has not been calculated theoretically, and it is not possible to compare our result with any theoretical predictions at this time.

Experim entally, however, an additional test for this unexpected behavior of F $_{\mathrm{0}}$ can be m ade from the M R m easurem ents under an in-plane magnetic eld (Bk). The in-plane M R provides a way to measure the e ective gfactor, which is directly related to F, by the relation $g = g_b = 1 = (1 + F_0)$, where g_b is the bare g-factor. Figure 3 (a) shows the in-plane MR measured in our sample for various densities at 65 m K . The M R increases as $\exp(B_k^2)$ at low B_k and $\exp(B_k)$ at high B_k , consistent with an earlier observation for 2D holes on (311)A GaAs¹⁴. Sim ilarly strong MR has also been observed for 2D electrons in Si-MOSFET 15 and the 2D electrons in GaAs¹⁶. It has been established that this crossover from low eld to high eld dependences corresponds to full spin polarization of the carriers¹⁷ and its position allows the determination of g. The crossover eld B, determined from the position where the second derivative of the vs B_k curve becomes maximum, is marked by an arrow for 10^{10} cm 2 in Fig. 3 (a), and the dependence of B on p is shown in Fig. 3 (b). For p > pc, B decreases linearly with decreasing p (best t given by the solid line), and saturates in the insulating side of the M II for p < pc. This behavior is also consistent with earlier observation by Yoon et al. for the 2D holes on (311)A. A dierent way of determining B, using the in ection point between high and low eld dependences, yields a result within the error bar of this plot, and produces an error of less than 15% in g.

For the metallic side, g determ ined from the relation $2E_F=g_BB$ (where E_F is the Ferm Lenergy and $_B$ is the Bohrm agneton) is shown in Fig. 3 (c) as a function of p. g decreases monotonically with decreasing p for the density range measured. The solid line in Fig 3 (c) is the result when the best linear tin Fig 3 (b) is used. Although a quantitative comparison between g in Fig 3 (c) and the value of g expected from F_0 cannot be made since the bare g-factor g_0 is not well known for holes in GaAs, we can qualitatively compare their density de-

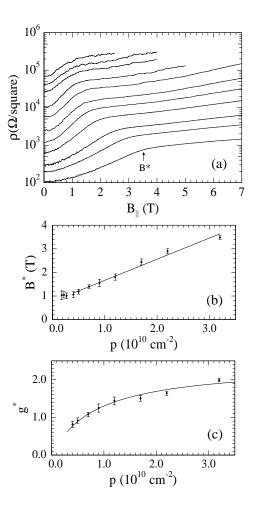


FIG. 3: (a) $vs\,B_k$ at T = 65 m K and p = 32,22,1.7,12,0.9,0.7,0.5,0.4,0.27,0.22, and 0.18 10^{10} cm 2 from the bottom .B is marked by an arrow for p = 32 10^{10} cm 2 . (b) B $vs\,p$. Solid line is a linear t to the data for m etallic side, p > p_c . (c) g determined from B . Solid line is the result obtained by the linear t in (b)

pendences. From the density dependence of F_0 shown in Fig.2 (b) and the relation $g=g_b=1=(1+F_0)$, we expect that g increases with decreasing p for $p^>2$ 10^{10} cm 2 and then decreases with decreasing p for p<2 10^{10} cm 2 . The behavior of g shown in Fig 3 (c), therefore, agrees well with that expected from F_0 for p<2 10^{10} cm 2 , where F_0 decreases in magnitude with decreasing p. While this region of p is where we have observed the unexpected density dependence of F_0 , in this region there is good agreement in the behavior of F_0 and g. Thus, our in-plane M R m easurements con m the unexpected behavior of F_0 found from the T dependence of

The decrease in magnitude of F_0 with decreasing p (increasing r_s) is of great interest, and needs further exam ination. We, therefore, have also analyzed our data without the assumption of a density independent mass $m=0.38 m_e$. In this analysis, we used three inde-

pendent relations (equation (1), $2E_F = g_B B$, and $g = g_b = 1 = (1 + F_0)$) between F_0 , m, and g to calculate each quantity. Since g_b is not well known, we used it as a parameter, and found that the density dependence of each quantity does not depend on a specic value of g_b while $g_b = 0.5$ gives the best quantitative agreement with F_0 and g determined earlier. From this analysis, F_0 also exhibits a nonmonotonic dependence on p. The magnitude of F_0 increases with decreasing p for F_0 on F_0 and decreases with decreasing p for F_0 on F_0 and decreases with decreasing p for F_0 in F_0 and F_0 in magnitude with decreasing p for F_0 is still observed and con med once again.

Any explanation for this surprising result should take into account the large $r_{\rm s}$ values in our system . For 37, the 2D system is expected to be a pinned W igner crystal. The critical density for MIT in our system corresponds to $r_s = 57$, considerably larger than the critical $r_{\rm s}$ predicted for this crystallization. The $r_{\rm s}$ values for which we observed the unexpected behavior of F nange between 22 and 37, close to that predicted for W igner crystallization. We note that there has been a Monte Carlo calculation 18 of Ferm i-liquid param eters for rs up to 5, where Fo still increases monotonically in magnitude with increasing $r_{\rm s}$. To our know ledge, there is no theoretical calculation of the dependence of F_0 on r_s when rs is large, relevant to our experiment. The question whether the crystallization is preceded by a ferrom agnetic instability with $F_0 =$ 1 has to be addressed as well. From Monte Carlo calculations, Tanatar and Ceperley have showed both possibilities of a diverging and a nite-valued spin susceptibility as rs increases toward the critical $r_{\rm s}$ for the W igner crystallization. Our result appears to imply that the ferrom agnetic instability does not occur in the large rs regime of our 2D hole system.

We now address the important issue of phonon scattering contribution to our measured hole resistivity, which we have ignored in our analysis. The question of phonon contribution to the resistivity is crucial since, if it is signi cant, it would then be im possible to com pare our measured resistivity to the interaction theory. We have therefore theoretically directly calculated the phonon scattering contribution by including both deformation potential and piezoelectric coupling of the 2D holes to GaAs acoustic phonons. Following ref. 19 we have carried out a detailed calculation of the phonon scattering contribution to the hole resistivity in the parameter range of our experiment with the results being shown in Fig. 4. Our theoretical phonon-only resistivity, as shown in Fig. 4, dem onstrates that for T 200m K, the tem perature regim e we concentrate on in com paring our experim ental resistivity with the interaction theory (see Fig. 2), the phonon contribution to the resistivity is miniscule (less than 1% of the measured resistivity). We are therefore justi ed in neglecting phonon scattering e ects in the discussion of our experim ental results as long as we restrict ourselves to T < 200m K as we have done in analyzing our data. As is obvious from our theoretical results pre-

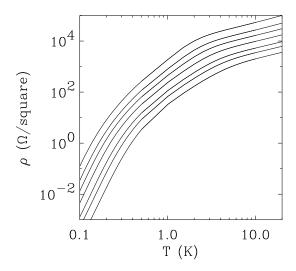


FIG. 4: Resistivity due to phonon scatterings (piezoelectric and deform ation potential coupling) as a function of tem perature. Here the lines corresponds to the hole density p=0.5, 0.7, 0.9, 1.2, 1.7, 2.2, 3.2 10^{10} cm 2 (from top to bottom).

sented in Fig. 4, hole-phonon scattering contribution to hole resistivity becomes non-negligible for T > 200 m K and is, in fact, signi cant for T = 500 m K with its quantitative in portance increasing with decreasing carrier density.

We should point out in this context that we disagree with the methodology employed recently by Proskuryakov et al. in subtracting out a calculated phonon scattering contribution to their measured resistivity in analyzing their hole transport data in the context of a quantitative comparison with the interaction theory of Zala et al.4. First, it is well-known²⁰ that Matthiessen's rule does not apply to 2D systems at nite tem peratures, and therefore, subtraction of phonon contribution (even if this contribution were accurately known, which is questionable) in order to obtain the nonphonon part is unjusti ed and may be subject to large errors. (This problem is worse in the presence of screening of hole-phonon interaction, which must be included in the theory.) Second, the calculation of phonon scattering contribution to hole resistivity, following ref. 21, carried out by Proskuryakov et al. 11 is rather crude and approximate (compared, for example, with our theoretical calculations shown in Fig. 4 of this paper). We

note that in ref. 11 the measured hole resistivity (before any phonon subtraction) hardly manifests any clear cut linear tem perature regime, and the subtracted phonon contribution is a large fraction of the measured resistivity, thereby casting substantial doubt on the accuracy of the subtracted resistivity eventually compared with the interaction theory. Our analysis in this work avoids these serious pitfalls of ref. 11 by directly considering the measured resistivity in the context of interaction theory, which we justify by explicitly calculating the phonon contribution to the hole resistivity in the tem perature range of our interest and showing it to be negligible so that no arbitrary and unjustiable phonon subtraction is required (in contrast to ref. 11).

W e calculate the tem perature dependence of the hole resistivity by considering screened acoustic-phonon scattering. We include both deform ation potential and piezoelectric coupling of the 2D holes to 3D acoustic phonons of GaAs. Details of the acoustic-phonon scattering theory are given in Ref. 19. In this calculation we use the param eters corresponding to G aAs: $c_1 = 5:14$ 10° cm/s, $c_t = 3.04$ 10^5 cm/s, = 5.3 g/cm³, $eh_{14} = 1.2$ eV/cm, and D = 8.0 eV. In the low tem perature range (T < 0.2K) we nd (T) / T 5 T⁷ because the deform ation potential scattering dom inates over piezoelectric coupling. In the intermediate temperature range (0.2K < T < $T_{\rm B\,G}$) we have $\,$ (T) / T 3 m ostly due to the piezoelectric scattering²¹. Above the Bloch-Gruneisen 1 2K, both scattering tem perature, $T_{BG} = 2k_F c_1 = k_B$ processes give rise to linear temperature dependence of the resistivity, (T) / T. The phonon contribution to the resistivity shows very weak temperature dependence and is negligible when the temperature is substantially below $T_{B,G}$. We emphasize that the phonon contribution to the resistivity cannot be linear for T $\,<\,T_{B\,G}$, and for 200m K the phonon contribution is negligible.

In sum m ary, we have measured the temperature dependence of the metallic conductivity of extremely high mobility dilute 2D holes in GaAs in large $r_{\rm s}$ limit. We not that the conductivity shows a linear dependence on temperature in the ballistic regime. The Fermi liquid interaction parameter F_0 obtained from our data is found to exhibit a nonmonotonic dependence on density and decrease in magnitude with increasing $r_{\rm s}$ for $r_{\rm s}$ $^>$ 22.

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¹ E.Abraham s, P.W. Anderson, D.C. Licciardello, and T. V.Ram akrishnan, Phys. Rev. Lett. 42, 673 (1979).

For a review, see B. L. Altshuler, D. L. Maslov, and V. M. Pudalov, Physica E (Amsterdam) 9(2), 209 (2001); E. Abrahams, S. V. Kravchenko, M. P. Sarachik, Rev. Mod. Phys. 73, 251 (2001).

 $^{^3\,}$ J.Yoon, C.C.Li, D.Shahar, D.C.Tsui, and M.Shayegan,

Phys.Rev.Lett.82,1744 (1999).

⁴ G. Zala, B. N. Narozhny, and I. L. Aleiner, Phys. Rev. B 64, 214204 (2001).

⁵ B.L.Altshuler, A.G.Aronov, and P.A.Lee, Phys.Rev. Lett. 44, 1288 (1980); H.Fukuyama, J.Phys.Soc.Jpn. 48, 2169 (1980); A.M.Finkelstein, Sov.Phys.JETP 57, 97 (1983) [Zh.Eksp.Teor.Fiz.84, 168 (1983)].

- ⁶ A. Gold and V. T. Dolgopolov, Phys. Rev. B 33, 1076 (1986); S. Das Sarma, Phys. Rev. B 33, 5401 (1986).
- ⁷ S.D as Sarm a and E.H.Hwang, Phys. Rev. Lett. 83, 164 (1999); Phys. Rev. B 61, R7838 (2000).
- ⁸ B.E.K ane et al, Appl. Phys. Lett. 63, 2132 (1993).
- ⁹ B. Tanatar and D. M. Ceperley, Phys. Rev. B 39, 5005 (1989).
- ¹⁰ H.L.Storm er et al., Phys. Rev. Lett. 51, 126 (1983).
- Y.Y.Proskuryakov, A.K.Savchenko, S.S.Safonov, M. Pepper, M.Y.Simmons, and D.A.Ritchie, Phys. Rev. Lett. 89, 076406 (2002).
- A.A. Shashkin, S.V. K ravchenko, V. T. Dolgopolov, and T. M. K lapwijk, cond-mat/0111478; S. A. Vitkalov, K. James, B. N. Narozhny, M. P. Sarachik, and T. M. K lapwijk, cond-mat/0204566; V. M. Pudalov, M. E. Gershenson, H. Kojima, G. Brunthaler, A. Prinz, and G. Bauer, cond-mat/0205449.
- P.T. Coleridge, A.S. Sachrajda, and P. Zawadzki, Phys. Rev. B 65, 125328 (2002).

- ¹⁴ J.Yoon, C.C.Li, D.Shahar, D.C.Tsui, and M.Shayegan, Phys. Rev. Lett. 84, 4421 (2000).
- D. Sim onian, S.V. Kravchenko, M. P. Sarachik, and V.M. Pudalov, Phys. Rev. Lett. 79, 2304 (1997).
- ¹⁶ E. Tutuc, S.M elinte, and M. Shayegan, Phys. Rev. Lett. 88,036805 (2002).
- T. O kam oto et al., Phys. Rev. Lett. 82, 3875 (1999); S. A.V itkalov et al., Phys. Rev. Lett. 85, 2164 (2000); V.T. Dolgopolov and A. Gold, JETP Lett. 71, 27 (2000); I.F. Herbut, Phys. Rev. B 63, 113102 (2001); E. Tutuc et al., Phys. Rev. Lett. 86, 2858 (2001).
- 18 Y. Kwon, D. M. Ceperley, and R. M. Martin, Phys. Rev. B 50, 1684 (1994).
- ¹⁹ T. Kawam ura and S.Das Sarma, Phys. Rev. B 42, 3725 (1990); Phys. Rev. B 45, 3612 (1992).
- ²⁰ F.Stem, Phys. Rev. Lett. 44, 1469 (1980).
- ²¹ V.Karpus, Sem icond. Sci. Technol. 5, 691 (1990).